

POWERFUL FIZEAU INTERFEROMETER

- High-accuracy measurement capability with unsurpassed flexibility and versatility
- Non-contact form and wavefront measurement

This is what we mean by **EXACTLY**.



EXACTLY

NON-CONTACT FORM AND WAVEFRONT MEASUREMENT



MarOpto FI 1040 Z with optional vertical measuring stand

More information www.mahr.com, WebCode: 21874 + 21875 +49(0)551 7073 800 info@mahr.com

OPTICAL MEASURING INSTRUMENT MAROPTO FI 1040 Z, 1100 Z, 1150 Z

The **MarOpto FI 1040 Z**, **FI 1100 Z** and **FI 1150 Z** are powerful interferometers that enable the non-contact measurement of flat or spherical surfaces and transmitted wavefront of optical components and assemblies.

Measurements can be performed using simple basic visual fringe inspection, IntelliPhase static spatial carrier analysis, or phase-modulated interferogram analysis.

MarOpto FI 1040 Z, **FI 1100 Z** and **FI 1150 Z** offer flexibility and excellent performance for handling today's industrial applications.



FEATURES

- 3x zoom / 6x zoom
- Total USB connectivity option with 1k x 1k true spatial resolution
- 3 modes of interferogram analysis: Phase shifting, IntelliPhase static spatial carrier analysis, or fringe tracing
- Vibration-insensitivity can be achieved using Mahr's IntelliPhase static spatial carrier recording and evaluation software
- Compatible with all industry standard 4" (100 mm) and 150 mm (6") reference optics and accessories (MarOpto FI 1100 Z and MarOpto FI 1150 Z)
- Small size allows easy integration into OEM systems
- Compact, rugged design
- High-accuracy measurements at an affordable price
- Configurations include horizontal, vertical look up and vertical look down. Optional workstations for flats and for radius of curvature measurements.





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MAROPTO FI 1040 Z FIZEAU INTERFEROMETER FOR FLAT OR SPHERICAL SURFACES



REFERENCE OPTICS

E/# the TC	Radius TS [mm]	
r/# uie is	λ/10	
0.7	17	
1	25	
2	64	
3	123	
4	131	
6	206	
TF: Ø 40 mm		

MEASURING TASKS

- Transmission and surface testing of small optics
- Measurements of the radii of curvature

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MAROPTO FI 1100 Z - HIGH ACCURACY MEASUREMENT CAPABILITY WITH UNSURPASSED FLEXIBILITY AND VERSATILITY



REFERENCE OPTICS

F/# the TC	Radius TS [mm]			
r/# the is	λ/10	λ/20		
0.55	19			
0.65	39			
0.74	47.6			
1	90			
1.5	120.4			
2.2	175.9			
2.4	264.5			
3.3	300			
4	370			
4.9	540			
5	450			
7.0	665			
7.1	800			
10.7	1200			
11	1050			
23	2329.8			
TF: Ø 100 mm				

MEASURING TASKS

- Measurement of flat, concave or convex surfaces
- Wedge angle and homogeneity measurements
- Transmission and surface testing of optics components
- Measurement of optics components, ceramic, and wafer surfaces
- Wavefront analysis of optical systems and components
- Measurements of the radii of curvature

More information www.mahr.com WebCode 21874 +49 (0) 551 7073 800 info@mahr.com

MarOpto | FI Series

MAROPTO FI 1150 Z EASY AND FAST INTERFEROMETRIC CHARACTERIZATION



REFERENCE OPTICS

E/# thats	Radius TS [mm]		
r/# mers	λ/10	λ/20	
0.75	72.09		
1.1	130.68		
1.6	220.35		
2.4	346.7		
3.5	518.3		
5	739.8		
7.4	1128		
TF: Ø 150 mm			

MEASURING TASKS

- Measurement of flat, concave or convex surfaces
- Wedge angle and homogeneity measurements
- Transmission and surface testing of optics components
- Measurement of optics components, ceramic, and wafer surfaces
- Wavefront analysis of optical systems and components
- Measurements of the radii of curvature

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MAROPTO INTELLIWAVE SOFTWARE HIGH PERFORMANCE INTERFEROMETRIC ANALYSIS SOFTWARE





DESCRIPTION

IntelliWave allows for the characterization of spherical optics, aspheric optics, machined parts, ceramics, semiconductor wafers, and analysis of optical wavefronts. Applications include measuring, flatness, irregularity, curvature, stress, and strain.

FEATURES

- Multiple polynomial sets (aberrations) for analysis
- Differentials and integrals
- Complex masking including unrestricted masking groups
- Fiducials and image transformations
- Measurement of wavefront, wedg, angle, prisms, 3-flattest, homogenity
- Optional interfaces: IDL™, LabVIEW™, Excel™
- IntelliPhase static spatial carrier analysis



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More information www.mahr.com WebCode 21907 +49 (0) 551 7073 800 info@mahr.com

MAROPTO FI SYSTEMS

TECHNICAL DATA

MarOpto FI - System	FI 1040 Z	FI 1100 Z	FI 1150 Z	
Beam diamter	38 mm	102 mm	150 mm	
Zoom	6x / 3x	бх	бх	
Focus	±1.5 m	± 2.0 m	± 2.0 m	
Intensity	adjustable			
Alignment	easy two-point alignment			
View to the alignment	±1.5°			
Display	live	e video on the computer screen		
Performance Parameters ¹				
RMS repeatability ²	1 nm			
Calibrated accuracy	λ / 100			
Height resolution	λ / 8000			
Lateral resolution	640 x 480 / 1k x 1k			
Digitalization	8 bit / 10 bit			
Recording time		300 ms		
Averaging methods		intensity and phase		
Laser				
Wavelength	632.8 n	m HeNe-Laser / stabilized HeNe la	aser	
Polarization		linear / circular		
Coherence	≥ 100 m			
Laser class	2			
Power supply, dimensions, weight				
Power supply	110 / 240 V; 50 / 60 Hz / < 155 Watt	110 / 240 V; 50 / 60 Hz / < 130 Watt	110 / 240 V; 50 / 60 Hz / < 130 Watt	
Dimension [mm]	335 x 195 x 160	421 x 190 x 256	604 x 304 x 316	
Weight	7.25 kg	14 kg	42 kg	
Environmental conditions ³				
Temperature	+15°C up to + 30°C			
Allowed temperature change	< 1.0°C pro 15 min			
Relative humidity	5% to 95%, non-condensing			
Vibration damping	required at frequencies 1Hz to 120 Hz			

1. Vibration-free environment with temperature change < 1°C / 15 min between 20°C and 23°C, no thermals

- 2. 1 σ repeatability accuracy of the RMS for 32 data sets, each as an average of 16 measurements
- 3. The system can be operated under these conditions; the conditions, however, are not the environmental conditions that are required for the best performance.

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MAROPTO FI SYSTEMS

CONFIGURATION POSSIBILITY

- Position-independent use, e.g. vertical and horizontal
- Static or dynamic phase shift

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• Option to measure the radii of curvature

WORKING PLACE STATION

- Powerful computer with software IntelliWave installed
- All hardware interfaces are set up to operate the MarOpto FI interferometer.

ACCESSORIES (DEPENDING ON THE SYSTEM)

- Complete set of reference optics
- Beam: 102 mm to 150 mm, 200 mm and 300 mm
- Isolations table
- Compatible with all standardized 4" reference optics





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PRODUCTION METROLOGY



MarOpto MT 100 / 100i

High-precision Fizeau interferometer measuring tower for the testing of spherical glass surface.

WebCode: 22065 www.mahr.com

MarOpto MT 150

WebCode: 22066

www.mahr.com

Highly precise Fizeau interferometer measuring tower for the testing of flat, spherical and optionally aspherical lenses.





MarOpto MT 150p High-precision Fizeau interferometer measuring tower for the testing of single plane surfaces or multiple carriers in optics production.

WebCode: 22068 www.mahr.com

MarOpto MT 150i

Highly precise Fizeau interferometer measuring tower for the testing of spherical and aspherical lenses with CGH.

> WebCode: 22067 www.mahr.com





MarOpto MT 50 A compact Fizeau workshop interferometer for the testing of spherical components in the production environment.

WebCode: 22064 www.mahr.com

Precimar SM 60 Length measuring bench

A user-friendly measuring instrument for fast, precise outside measurements on workpieces.



WebCode: 22735 www.mahr.com

MarSurf UD 130 Aspheric 2D Precision 2D measuring station for measuring and evaluating optical components.

WebCode: 22044 www.mahr.com

MarForm MFU 200 Aspheric

High-precision contour measurement of spheres and aspheres. 3D determination of form error early in production process.







Mahr

MarSurf LD 130 / 260 Aspheric 2D / 3D High-precision contour measurement of spheres and aspheres. 3D determination of form error early in production process.

WebCode: 21880 www.mahr.com MarOpto TWI 60 Tilted wave interferometer for fast and highly accurate measurement of aspheres.

WebCode: 21879 www.mahr.com



MarOpto | FI Series

PRODUCTION METROLOGY



MarSurf WM 100

Optical roughness measurement on highly polished optical components in the nanoscale range.

WebCode: 20565 www.mahr.com

MarSurf CWM 100

WebCode: 20566

www.mahr.com

MarVision SM 150 / 151

Stereo zoom microscope with

digital camera for detecting

User-friendly, high-precision contactless topography measurement on optical components.





MarVision MM 420 Stereo zoom microscope for detecting defects on large lenses.

WebCode: 20875 www.mahr.com WebCode: 21050 www.mahr.com

defects.





MarSurf XR 1 Mobile roughness measurement with Bluetooth between drive unit and evaluation unit.

WebCode: 20555 www.mahr.com MarVision MM 320 Video workshop measuring microscope. High precision for your quality control.

> WebCode: 20874 www.mahr.com





MarVision QM 300 Video workshop measuring microscope. High precision for your quality control.

WebCode: 20879 www.mahr.com MarSurf CM expert Powerful confocal microscope for the threedimensional measurement and analysis of surfaces.

> WebCode: 22662 www.mahr.com





MarCator Digital and Dial Indicators Its easy handling makes it one of the most diverse tools for everyday testing.

WebCode: 20234 www.mahr.com MarCal Calipers Digital and mechanical calipers for inner, outer and step measurements.

> WebCode: 20066 www.mahr.com



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MarOpto | FI Series





Partner of manufacturing companies worldwide.

Got QUESTIONS? Want more INFORMATION?

Call us on +49 (0) 551 7073 800, or email us at info@mahr.com



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